


<b>Search Notes</b>  	<b>Application/Control No.</b>  10781910	<b>Applicant(s)/Patent Under Reexamination</b>  PEYRUCAIN ET AL.
	<b>Examiner</b>  BENJAMIN P LEE	<b>Art Unit</b>  3641

SEARCHED			
Class	Subclass	Date	Examiner
244	185	1/27/2008	LEE
244	186	1/27/2008	LEE
244	187	1/27/2008	LEE
244	195	1/27/2008	LEE
701	3	8/16/2008	LEE
701	14	8/16/2008	LEE
701	15	8/16/2008	LEE
701	16	8/16/2008	LEE
701	120	8/16/2008	LEE
244	194	12/2/2008	LEE
701	18		LEE

SEARCH NOTES		
Search Notes	Date	Examiner
updated search	1/27/2008	LEE
updated search	8/16/2008	LEE
updated search	12/2/2008	LEE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
244	185	12/2/2008	LEE
244	186	12/2/2008	LEE
244	187	12/2/2008	LEE
244	195	12/2/2008	LEE
701	3	12/2/2008	LEE
701	14	12/2/2008	LEE
701	15	12/2/2008	LEE
701	16	12/2/2008	LEE
701	120	12/2/2008	LEE
701	18	12/2/2008	LEE
244	194	12/2/2008	LEE

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